## SN54276, SN74276 QUADRUPLE J.K FLIP-FLOPS

SDLS091

OCTOBER 1976 - REVISED MARCH 1988

- Four J-K Flip-Flops in a Single Package . . .
  Can Reduce FF Package Count by 50%
- Separate Negative-Edge-Triggered Clocks with Hysteresis... Typically 200 mV
- Typical Clock Input Frequency . . . 50 MHz
- Fully Buffered Outputs

#### description

These quadruple TTL J-K flip-flops incorporate a number of third-generation IC features that can simplify system design and reduce flip-flop package count by up to 50%. They feature hysteresis at each clock input, fully buffered outputs, and direct clear capability, and are presettable through a buffer that also features an input hysteresis loop. The negative-edge-triggering clocks are directly compatible with earlier Series 54/74 single and dual pulse-triggered flip-flops. These circuits can be used to emulate D- or T-type flip-flops by hard-wiring the inputs, or to implement asychronous sequential functions.

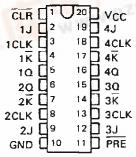
The SN54276 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C; the SN74726 is characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C.

FUNCTION TABLE (EACH FLIP-FLOP)

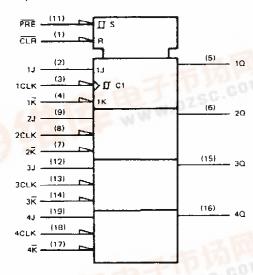
COMMON INPUTS		INPUTS			QUTPUT		
PRE	CLR	CLK	1	ĸ	a		
L	Н	Х	Х	Х	H		
н	L	X	X	X	- 4.14		
L	L	x	Х	Х	H <sup>†</sup>		
Н	H	A 100 miles	L	Н	Ω0		
Н	Н	1	Н	Н	н		
Н	Н	ı	L	L	L		
н	H	1	Н	L	TOGGLE		
Н	Н	н	×	×	G <sub>0</sub>		

<sup>&</sup>lt;sup>†</sup> This configuration is nonstable; that is, it may not oersist when preset and clear return to their inactive (high) level.

SN54276 . . . J PACKAGE SN74276 . . . N PACKAGE (TOP VIEW)



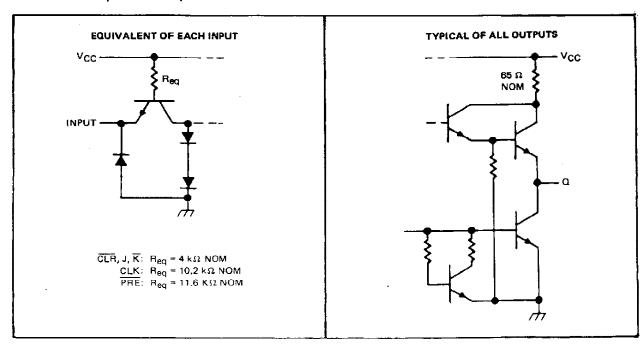
## logic symbol‡



\*This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



## schematics of inputs and outputs



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)		7 V
Input voltage		5.5 V
	SN54276	
	\$N74276	0° C to 70° C
Storage temperature range		- 65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

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### recommended operating conditions

. . . .-

		SN54276		SN74276			UNIT	
	_	MIN	NOM	MAX	MIN	NOM	MAX	UNII
Supply voltage, VCC		4.5	5	5.5	4,75	5	5.25	V
High-level output current, IOH				-800			-800	μА
Low-level output current, IOI		· · · · · · · · · · · · · · · · · · ·		16			16	mA
Clock frequency		0	·	35	0		35	MHz
	Clock high	13.5			13,5			
Pulse width, tw	Clock low	15			15			ns
• ••	Preset or clear low	12			12			
Setup time, t <sub>SU</sub>	J, K inputs	31			34			ns
	Clear and preset inactive state	10↓			101			
Input hold time, th		10↓		,	104			ns
Operating free-air temperature, TA		-55		125	0		70	°C

<sup>1</sup> The arrow indicates that the falling edge of the clock pulse is used for reference.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONST		MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage			2		<del></del> -	V
VIL	Low-level input voltage					8.0	٧
VIK	Input clamp voltage	V <sub>CC</sub> = MIN,	1 <sub>1</sub> = -12 mA			-1.5	٧
∨он	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V,	V <sub>IH</sub> ≈ 2 V, I <sub>OH</sub> = −800 µA	2.4	3.4		V
VOL	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>1L</sub> = 0.8 V,	V <sub>IH</sub> = 2 V, I <sub>OL</sub> = 16 mA		0.2	0,4	V
l <sub>1</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 5.5 V		-	1	mA
Чн	High-level input current	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.4 V			40	μА
₹1L	Low-level input current	V <sub>CC</sub> ≃ MAX,	V <sub>1</sub> = 0.4 V	1		-1,6	mΑ
los	Short-circuit autput current§	V <sub>CC</sub> ≈ MAX		-30	• •	85	mΑ
1cc	Supply current	V <sub>CC</sub> = MAX			60	81	mA
~~		1					

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.  $\ddagger$ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25 \,^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f	Maximum clock frequency		35	50		MHz
<sup>1</sup> max tpt H	Propagation delay time, low-to-high-level output from preset	C <sub>L</sub> = 15 pF,		15	25	ns
<sup>t</sup> PHL	Propagation delay time, high-to-low-level output from clear	R <sub>L</sub> ≈ 400 Ω.		18	30	ns
<sup>t</sup> PLH	Propagation delay time, low-to-high level output from clock	See Note 2		17	30	ns
tPHL	Propagation delay time, high-to-low level output from clock			20	30	กร

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>§</sup>Not more than one output should be shorted at a time.

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